Search Notes



Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/816,640	KITAHARA ET AL.	
Examiner	Art Unit	
Binh C. Tat	2825	

SEARCHED				
Class	Subclass	Date	Examiner	
716	9,11,17	2/2/2007	вт	
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
716	9,11,17	2/2/2007	ВТ	
	ext seach- , 2007 see ce search	2/2/2007	ВТ	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
EAST SEARCH (text search only see history searching printout)	2/2/2007	ВТ		
IÉEE	2/2/2007	ВТ		
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